Notice of References Cited

Application/Control No. 10/067,320	Reexamination	Applicant(s)/Patent Under Reexamination WATANABE ET AL.		
Examiner	Art Unit			
Andy Huynh	2818	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	[*] Name	Classification
	Α	US-6529670 B1	03-2003	Saito et al.	385/137
	В	US-6528864 B1	03-2003	Arai	257/620
	С	US-6513564 B2	02-2003	Bryan et al.	156/584
	D	US-6021267	02-2000	Bonn et al.	395/500.22
	Е	US-5777386	07-1998	Higashi et al.	257/737
	F	US-5661316	08-1997	Kish, Jr. et al.	257/190
	G	US-5341024	08-1994	Rosotker	257/620
	н	US-5327517	07-1994	Yamada et al.	385/137
	_	US-5223741	06-1993	Bechtel et al.	257/678
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				•	
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U			
	v			
	w			
	х			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.